Semiconductor Design to Test – Closing the Gap to Lab and Production Test

Coseda User Group Meeting 2016

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18 Oktober 2016



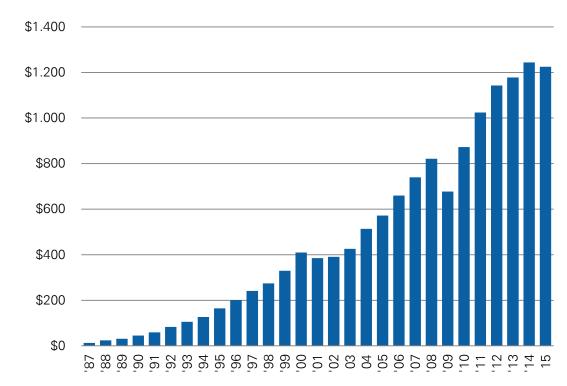
# Long-Term Track Record of Growth

Revenue: \$1.23 billion in 2015

**Global Operations:** Approximately 7,400 employees; operations in almost 50 countries

**Broad customer base**: More than 35,000 companies served annually

**Diversity**: No industry >15% of revenue



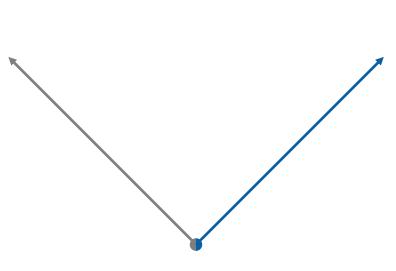


### A Platform Based-Approach

#### CLOSED APPROACH

"Vendor knows best"

- Fixed-functionality box instruments
- Extend with **vendor accessible** customization
- Fixed software applications
- Monolithic instrument
  design
- Resulting closed vendor ecosystem



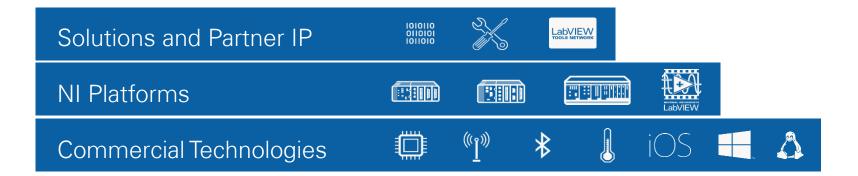
#### P L A T F O R M A P P R O A C H

"Customer knows best"

- Out of box measurement ready
- Extend with **user** accessible customization
- Productive, approachable software tools
- Modular instrument design with consistent APIs
- Resulting open partner, user, and IP ecosystem



### A Platform-Based Approach





### Architecture of an Automated Test System

NI TestStand/TestStand Semiconductor Module

Sequencing, Test Management, Test Deployment, STDF Reporting, User Management

SOFTWARE



Graphical IDE with measurement and analysis libraries and UI design

NI LabWindows<sup>TM</sup>/CVI ANSI C IDE with measurement and

analysis libraries and UI design

#### Other Software C, C++, C#, .NET, Python,

Measurement Studio

#### Instrument and Measurement Driver

IVI, VISA, NI-DAQ, NI-DMM, NI-SCOPE, NI-FGEN, NI-HSDIO, NI-RFmx, 3rd Party Hardware

HARDWARE

Multicore<br/>ControllersTiming and<br/>SynchronizationTest Cell<br/>IntegrationPXI<br/>InstrumentationImage: SynchronizationImage: Synchron

3<sup>rd</sup> Party Instrumentation



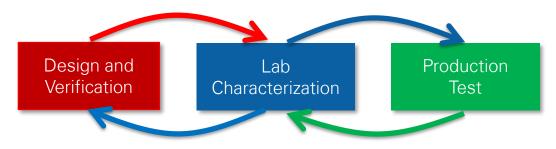
Condition

Monitorina



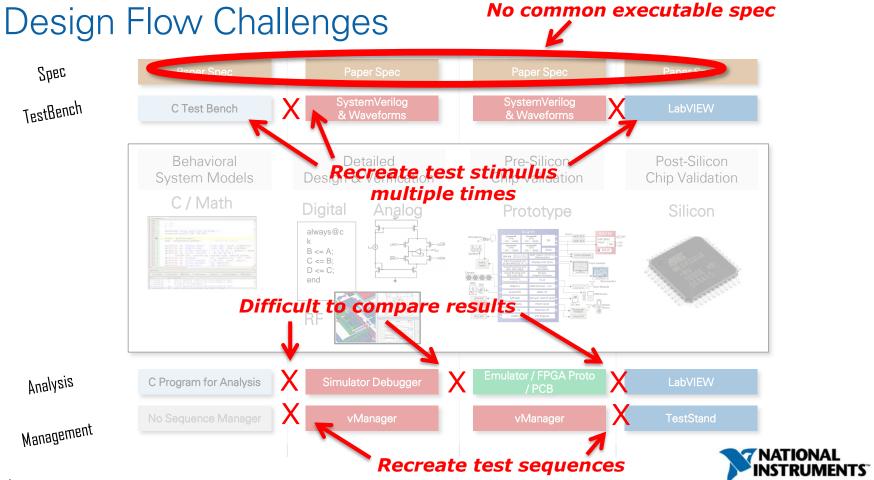


# Our Customers Are Telling Us...

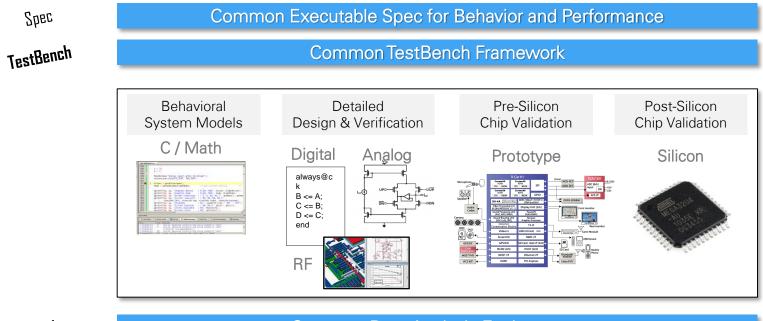


- Big gap between design, lab test and production test Different people, languages, tools, methodologies and databases
- · Significant effort to re-create test cases in the lab
- Difficult to reproduce failures in the engineering world and correlate results in simulation, lab test and production test





### Design Flow Goal: "IP" Re-Use



Analysis

Management

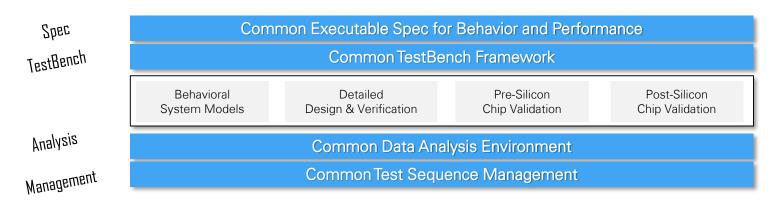
Common Data Analysis Environment

**Common Test Sequence Management** 



# Two Significant Benefits Between Design & Lab

#### **Improved Productivity**





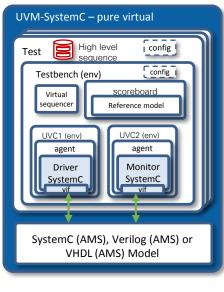


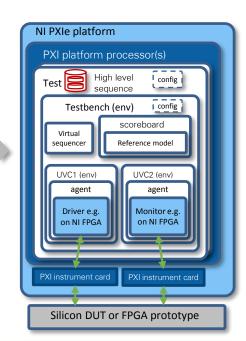
#### D2T with COSEDA – One Concept Idea











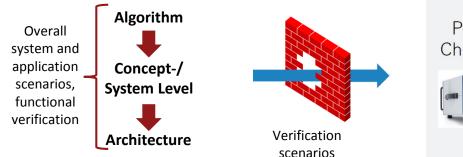
- Re-use SystemC / SystemC AMS testbenches in NI lab and/or test equipment – run the testbench on the real-time processor
- Using a UVM (or UVM like) concepts based on transactions
- Driver and monitor for NI PXIe based platform e.g. implemented on NI platform XILINX FPGA



# D2T System Level Design to Post-Silicon Validation















### Design to Test - Summary

- D2T establishes seamless path from pre-silicon to post-silicon
- Significant cost saving and development time shortening
- · Improved quality, predictability and traceability from pre- to post-silicon
- · Focus on data analysis across the flow and portable stimulus
- Re-use of tests from System/Concept design improves post-silicon validation
- Re-use of stimuli from implementation level design improves production test development

